

EMC Test Report

Client Name : **Shenzhen JHC Technology Development Co., LTD**

Client Address : **B Area, 3rd floor, A Block Junxiangda Building, N0.9 Zhongshanyuan Road, Nanshan Distr., Shenzhen, China**

Product Name : **Industrial Touch panel**

Report Date : **Sept. 21, 2022**

Shenzhen Anbotech Compliance Laboratory Limited



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TEST REPORT

Applicant : Shenzhen JHC Technology Development Co.,LTD
Manufacturer : Shenzhen JHC Technology Development Co.,LTD
Product Name : Industrial Touch panel
Test Model No. : ALAD-A1001T/S001-G
Reference Model No. : ALAD-A1001T/S002-G, ALAD-A1001T/T001-G, ALAD-A1001T/T002-G,
ALAD-A1001T(P)/S001-G, ALAD-A1001T(P)/S002-G,
ALAD-A1001T(P)/T001-G, ALAD-A1001T(P)/T002-G
Trade Mark : JHCTECH
Rating(s) : DC 12V, 1.1A, 13.2W
Test Standard(s) : EN 55032: 2015+A1:2020;
EN IEC 61000-3-2: 2019/A1:2021;
EN 61000-3-3: 2013+A1:2019+A2:2021;
EN 55035: 2017+A11:2020;
(IEC 61000-4-2; IEC 61000-4-3; IEC 61000-4-4;
IEC 61000-4-5; IEC 61000-4-6; IEC 61000-4-8; IEC 61000-4-11)

The device described above is tested by Shenzhen Anbotech Compliance Laboratory Limited to determine the maximum emission levels emanating from the device and the severe levels of the device can endure and its performance criterion. The measurement results are contained in this test report and Shenzhen Anbotech Compliance Laboratory Limited is assumed full of responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT (Equipment Under Test) is technically compliant with the EN 55032, EN IEC 61000-3-2, EN 61000-3-3, EN 55035 requirements.

This report applies to above tested sample only and shall not be reproduced in part without written approval of Shenzhen Anbotech Compliance Laboratory Limited.

Date of Receipt: Sept. 08, 2022

Date of Test: Sept. 08~Sept. 15, 2022

Prepared By:

Yee Huang

(Yee Huang)

Approved & Authorized Signer:

KingKong Jin

(KingKong Jin)



1. General Information

1.1. Client Information

Applicant	:	Shenzhen JHC Technology Development Co., LTD
Address	:	B Area, 3rd floor, A Block Junxiangda Building, N0.9 Zhongshanyuan Road, Nanshan Distr., Shenzhen, China
Manufacturer	:	Shenzhen JHC Technology Development Co., LTD
Address	:	B Area, 3rd floor, A Block Junxiangda Building, N0.9 Zhongshanyuan Road, Nanshan Distr., Shenzhen, China
Factory	:	Shenzhen JHC Technology Development Co., LTD
Address	:	B Area, 3rd floor, A Block Junxiangda Building, N0.9 Zhongshanyuan Road, Nanshan Distr., Shenzhen, China

1.2. Description of Device (EUT)

Product Name	:	Industrial Touch panel
Test Model No.	:	ALAD-A1001T/S001-G
Reference Model No.	:	ALAD-A1001T/S002-G, ALAD-A1001T/T001-G, ALAD-A1001T/T002-G, ALAD-A1001T(P)/S001-G, ALAD-A1001T(P)/S002-G, ALAD-A1001T(P)/T001-G, ALAD-A1001T(P)/T002-G (Note: All samples are the same except the touch screen type & color, so we prepare "ALAD-A1001T/S001-G" for test only.)
Trade Mark	:	JHCTECH
Test Power Supply	:	AC 230V, 50Hz
Test Sample No.	:	1-1-1
Product Description	:	Model: PA-60DC12 Input: 100-240V~,50/60Hz, 1.7A Output: +12.0V---5.0A
Remark: (1) For a more detailed features description, please refer to the manufacturer's specifications or the User's Manual. (2)The test report 18230EC20224001-M1 supersedes the test report 18230EC20224001 which is withdrawn.		



1.3. Auxiliary Equipment Used During Test

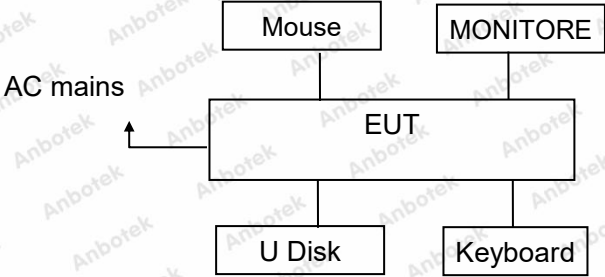
MONITOR	:	Manufacturer: PHILIPS
	:	M/N: 273V7QDSBF/93 S/N: UK0A2120004629A2K Input: AC100-240~50/60Hz 1.6A
KEYBOARD	:	Manufacturer: DELL
	:	M/N: SK-8120 S/N: CN-0DJ365-71616-49J-0MVR-A00 Input Rating: DC 5V, 0.05A CE, FCC, VCCI, KCC, TUV-GS Cable: 1.8m, unshielded



1.4. Description of Test Mode

Pretest Mode	Description
Mode 1	On

For Mode 1 Block Diagram of Test Setup



1.5. Test Summary

Test Items	Test Mode	Status
Power Line Conducted Emission Test	Mode 1	P
Asymmetric Mode Conducted Emission at Telecom Port	Mode 1	P
Radiated Emission Test (Below 1 GHz)	Mode 1	P
Radiated Emission Test (Above 1GHz)	Mode 1	P
Harmonic Current Test	/	N
Voltage Fluctuations & Flicker Test	Mode 1	P
Electrostatic Discharge Immunity Test	Mode 1	P
RF Field Strength Immunity Test	Mode 1	P
Electrical Fast Transient/Burst Immunity Test	Mode 1	P
Surge Immunity Test	Mode 1	P
Injected Currents Susceptibility Test	Mode 1	P
Power frequency Magnetic Field Immunity Test	/	N
Voltage Dips and Interruptions Immunity Test	Mode 1	P
P) Indicates "PASS". F) Indicates "Fail". N) Indicates "Not applicable".		



1.6. Test Equipment List☒ Power Line Conducted Emission Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	L.I.S.N. Artificial Mains Network	Rohde & Schwarz	ENV216	100055	Oct. 22, 2021	1 Year
2.	Three Phase V-type Artificial Power Network	CYBERTEK	EM5040DT	E215040D T001	Jul. 05, 2022	1 Year
3.	EMI Test Receiver	Rohde & Schwarz	ESCI	100627	Oct. 22, 2021	1 Year
4.	RF Switching Unit	Compliance Direction	RSU-M2	38303	Oct. 22, 2021	1 Year
5.	Software Name EZ-EMC	Ferrari Technology	ANB-03A	N/A	N/A	N/A

☒ Asymmetric Mode Conducted Emission at Telecom Port

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	ISN	Schwarzbeck	NTFM 8158	#172	Oct. 22, 2021	1 Year
2.	EMI Test Receiver	Rohde & Schwarz	ESCI	100627	Oct. 22, 2021	1 Year
3.	RF Switching Unit	Compliance Direction	RSU-M2	38303	Oct. 22, 2021	1 Year
4.	Software Name EZ-EMC	Ferrari Technology	ANB-03A	N/A	N/A	N/A
5.	Three Phase V-type Artificial Power Network	CYBERTEK	EM5040DT	E215040D T001	Jul 05, 2022	1 Year

☒ Radiated Emission Test (Below 1 GHz)

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	EMI Test Receiver	Rohde & Schwarz	ESR26	101481	Oct. 22, 2021	1 Year
2.	Pre-amplifier	SONOMA	310N	186860	Oct. 22, 2021	1 Year
3.	Bilog Broadband Antenna	Schwarzbeck	VULB9163	VULB 9163-289	Oct. 22, 2021	2 Year
4.	Software Name EZ-EMC	Ferrari Technology	ANB-03A	N/A	N/A	N/A



☒ Radiated Emission Test (Above 1GHz)

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	EMI Test Receiver	Rohde & Schwarz	ESR26	101481	Oct. 22, 2021	1 Year
2.	Bilog Broadband Antenna	Schwarzbeck	VULB9163	VULB 9163-289	Oct. 22, 2021	2 Year
3.	Pre-amplifier	SONOMA	310N	186860	Oct. 22, 2021	1 Year
4.	Software Name EZ-EMC	Ferrari Technology	ANB-03A	N/A	N/A	N/A
5.	Preamplifier	SKET Electronic	BK1G18G30D	KD17503	Oct. 22, 2021	1 Year
6.	Double Ridged Horn Antenna	Instruments corporation	GTH-0118	351600	Oct. 22, 2021	2 Year

☒ Harmonic Current and Flicker Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Programmable AC Power source	IVYTECH	APS-5005A	632734	Oct. 22, 2021	1 Year
2.	Harmonic and Flicker Analyzer	EMC-PARTNER	HMONICS 1000-1P	164	Oct. 22, 2021	1 Year
3.	Harmonics-1000	N/A	Ed.3.0+4.0	N.A	N/A	N/A

☒ Electrostatic Discharge Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	ESD Simulators	emtest	ESD NX30.1	11936	Mar. 25, 2022	1 Year

☒ RF Field Strength Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Signal Generator	Agilent	N5182A	MY48180656	Oct. 22, 2021	1 Year
2.	Amplifier	Micotoop	MPA-80-100 0-250	MPA1903096	Oct. 22, 2021	1 Year
3.	Amplifier	Micotoop	MPA-1000-6 000-100	MPA1903122	Oct. 22, 2021	1 Year
4.	Log-Periodic Antenna	Schwarzbeck	VULP9118E	00992	N/A	N/A
5.	Horn Antenna	Instruments corporation	GTH-0118	351600	Oct. 22, 2021	2 Year
6.	Power Sensor	Agilent	E9301A	MY41498906	Oct. 22, 2021	1 Year
7.	Power Sensor	Agilent	E9301A	MY41498088	Oct. 22, 2021	1 Year
8.	Power Meter	Agilent	E4419B	GB40202909	Oct. 22, 2021	1 Year
9.	Electric field Probe	Narda	EP 601	811ZX10351	Oct. 22, 2021	1 Year
10.	RS Test software	EMtrace	EM 3	V1.1.7	N/A	N/A



☒ Electrical Fast Transient/Burst Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Surge Generator	TESEQ	NSG 3060	1480	Oct. 22, 2021	1 Year
2.	CDN	TESEQ	CDN 3061	1408	Oct. 22, 2021	1 Year
3.	EFT-Clamp	PRIMA	EFT-Clamp	/	Oct. 22, 2021	1 Year

☒ Surge Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Combined Wave Lightning Surge Simulator	3Ctest	CCS600	ES3771702	Jul. 05, 2022	1 Year
2.	Three Phase Power Coupling Network	3Ctest	SEP69100 T	ES0801757	Jul. 05, 2022	1 Year
3.	Telecom port surge generator	PMI	TW101	190411	May 13, 2022	1 Year

☒ Injected Currents Susceptibility Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	C/S Conducted Immunity Test System	FRANKONIA	CIT-10	126A1196/2012	Oct. 22, 2021	1 Year
2.	CDN	FRANKONIA	CDN - M2+ M3	A2210178/2012	Oct. 22, 2021	1 Year
3.	6dB Attenuator	FRANKONIA	DAM 26W	1172202	Oct. 22, 2021	1 Year
4.	CIT-10	FRANKONIA	Version1.1.7	N/A	N/A	N/A
5.	EM-Clamp	FRANKONIA	EMCL-20	18101728-0103	May 17,2022	1 Year

☐ Power frequency Magnetic Field Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Power Frequency Magnetic Field Generator	EVERFINE	EMS61000-8 K	906002	Oct. 22, 2021	1 Year

☒ Voltage Dips and Interruptions Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	CYCLE SAG Simulator	PRIMA	DRP61011A G	PR12046234	Oct. 22, 2021	1 Year



1.7. Description of Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

FCC-Registration No.: 184111

Shenzhen Anbotech Compliance Laboratory Limited, EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No. 184111.

ISED-Registration No.: 8058A

Shenzhen Anbotech Compliance Laboratory Limited, EMC Laboratory has been registered and fully described in a report filed with the (ISED) Innovation, Science and Economic Development Canada. The acceptance letter from the ISED is maintained in our files. Registration 8058A.

Test Location

Shenzhen Anbotech Compliance Laboratory Limited.

1/F, Building D, Sogood Science and Technology Park, Sanwei community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China.518128



1.8. EMS Performance Criteria

Performance criterion A

The equipment shall continue to operate as intended without operator intervention. No degradation of performance, loss of function or change of operating state is allowed below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

Performance criterion B

During the application of the disturbance, degradation of performance is allowed. However, no unintended change of actual operating state or stored data is allowed to persist after the test.

After the test, the equipment shall continue to operate as intended without operator intervention; no degradation of performance or loss of function is allowed, below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

If the minimum performance level (or the permissible performance loss), or recovery time, is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

Performance criterion C

Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. A reboot or re-start operation is allowed.

Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.



2. Power Line Conducted Emission Test

2.1. Test Standard and Limit

Test Standard:	EN 55032
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☒ Limits for conducted emission at the AC mains power ports of Class A equipment

Frequency (MHz)	Limits (dB μ V)	
	Quasi-peak Level	Average Level
0.15 ~ 0.50	79.0	66.0
0.50 ~ 30.00	73.0	60.0

Remark: The lower limit shall apply at the transition frequencies.

☐ Limits for conducted emission at the AC mains power ports of Class B equipment

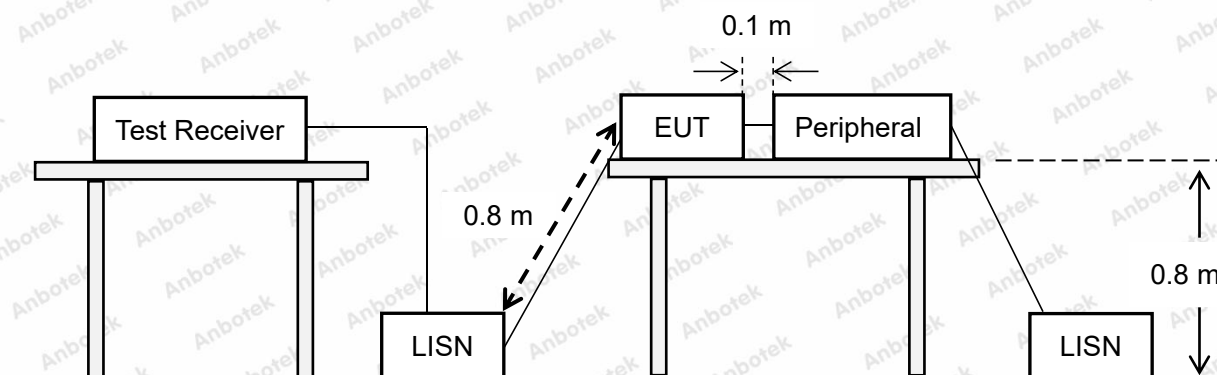
Frequency (MHz)	Limits (dB μ V)	
	Quasi-peak Level	Average Level
0.15 ~ 0.50	66.0 ~ 56.0 *	56.0 ~ 46.0 *
0.50 ~ 5.00	56.0	46.0
5.00 ~ 30.00	60.0	50.0

Remark:

(1) The lower limit shall apply at the transition frequencies.

(2) The limit decreases linearly with the logarithm of the frequency in the range 0.15MHz to 0.50MHz.

2.2. Test Setup



2.3. Test Procedure

The table-top EUT is placed on a non-conductive table 0.8 m above the horizontal ground reference plane, and the back of the EUT is 0.4 m away from the vertical ground reference plane, and at least 0.8 m from any other metal surface or ground plane. The floor-standing EUT is placed on an insulating support 0.1 m above the horizontal ground reference plate, at least 0.8 m away from other metal objects.

Connect EUT to the power mains through an LISN. Where the mains cable supplied by the manufacturer is longer than 1 m, the excess should be folded at the center into a bundle no longer than 0.4 m, so that its length is shortened to 1 m. All the peripherals are connecting to the other LISN.

The initial testing identified the frequency that has the highest disturbance relative to the limit while operating the EUT in typical modes of operation and cable positions in a test setup representative of typical system configuration.

The identification of the frequency of highest disturbance with respect to the limit was found by investigating disturbances at a number of significant frequencies. The probable frequency of maximum disturbance had been found and that the associated cable and EUT configuration and mode of operation had been identified.

Set the test-receiver to quasi peak detect function and average detect function, and to measure the conducted emissions values.

2.4. Test Results

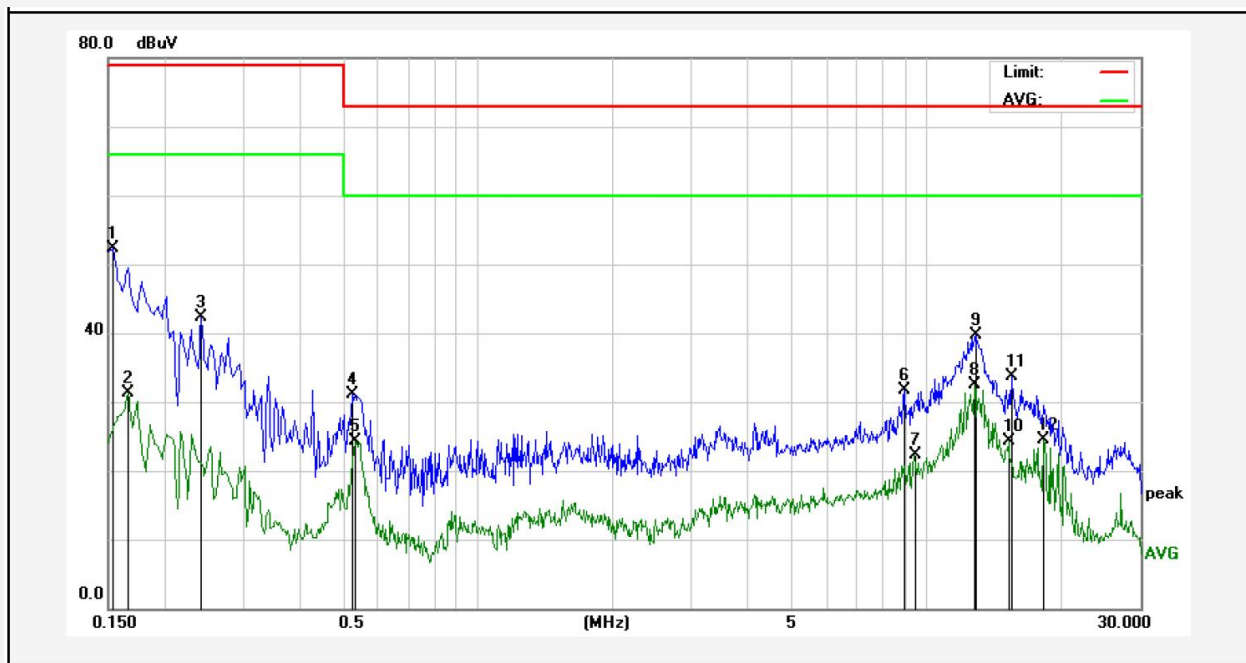
PASS

The test curves are shown in the following pages.



Power Line Conducted Test Data

Test Site: 1# Shielded Room
Test Specification: AC 230V, 50Hz
Comment: Live Line
Temp.: 23.5°C Hum.: 48%



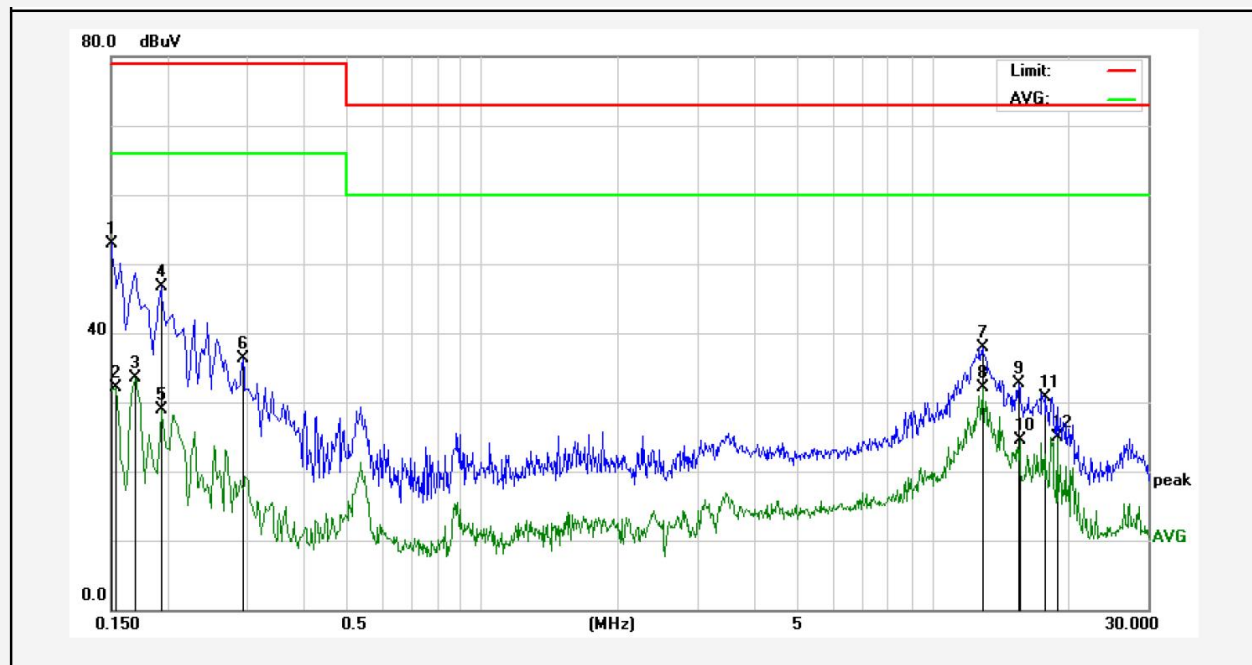
No.	Freq. (MHz)	Reading (dBuV)	Factor (dB)	Result (dBuV)	Limit (dBuV)	Over Limit (dB)	Detector	Remark
1	0.1539	42.58	9.70	52.28	79.00	-26.72	QP	
2	0.1660	21.52	9.70	31.22	66.00	-34.78	AVG	
3	0.2420	32.58	9.71	42.29	79.00	-36.71	QP	
4	0.5260	21.31	9.76	31.07	73.00	-41.93	QP	
5	0.5340	14.49	9.76	24.25	60.00	-35.75	AVG	
6	8.9580	21.84	9.82	31.66	73.00	-41.34	QP	
7	9.4340	12.47	9.82	22.29	60.00	-37.71	AVG	
8	12.8139	22.61	9.92	32.53	60.00	-27.47	AVG	
9	12.8740	29.80	9.92	39.72	73.00	-33.28	QP	
10	15.2500	14.31	9.99	24.30	60.00	-35.70	AVG	
11	15.4900	23.64	10.00	33.64	73.00	-39.36	QP	
12	18.2420	14.49	10.07	24.56	60.00	-35.44	AVG	

Note: Result = Reading + Factor Over Limit = Result - Limit



Power Line Conducted Test Data

Test Site: 1# Shielded Room
Test Specification: AC 230V, 50Hz
Comment: Neutral Line
Temp.: 23.5°C Hum.: 48%



No.	Freq. (MHz)	Reading (dBuV)	Factor (dB)	Result (dBuV)	Limit (dBuV)	Over Limit (dB)	Detector	Remark
1	0.1500	43.14	9.69	52.83	79.00	-26.17	QP	
2	0.1539	22.34	9.70	32.04	66.00	-33.96	AVG	
3	0.1700	23.80	9.71	33.51	66.00	-32.49	AVG	
4	0.1940	36.99	9.71	46.70	79.00	-32.30	QP	
5	0.1940	19.28	9.71	28.99	66.00	-37.01	AVG	
6	0.2940	26.62	9.72	36.34	79.00	-42.66	QP	
7	12.8740	28.03	9.92	37.95	73.00	-35.05	QP	
8	12.8740	22.21	9.92	32.13	60.00	-27.87	AVG	
9	15.4940	22.63	10.00	32.63	73.00	-40.37	QP	
10	15.6180	14.56	10.00	24.56	60.00	-35.44	AVG	
11	17.6980	20.61	10.06	30.67	73.00	-42.33	QP	
12	18.9140	14.82	10.09	24.91	60.00	-35.09	AVG	

Note: Result = Reading + Factor Over Limit = Result - Limit



3. Asymmetric Mode Conducted Emission at Telecom Port

3.1. Test Standard and Limit

Test Standard	EN 55032
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☒ Limits for asymmetric mode conducted emissions of Class A equipment

Frequency (MHz)	Limits (dB μ V)	
	Quasi-peak Level	Average Level
0.15 ~ 0.50	97.0 ~ 87.0 *	87.0 ~ 74.0 *
0.50 ~ 30.00	87.0	74.0

Remark:

The limit decreases linearly with the logarithm of the frequency in the range 0.15MHz to 0.50MHz.

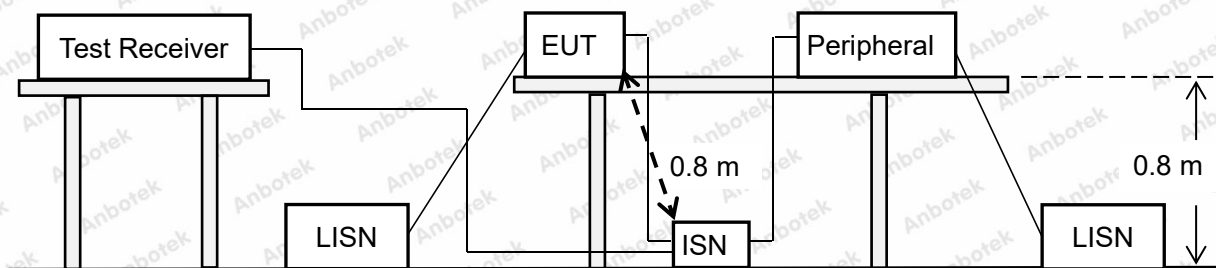
☐ Limits for asymmetric mode conducted emissions of Class B equipment

Frequency (MHz)	Limits (dB μ V)	
	Quasi-peak Level	Average Level
0.15 ~ 0.50	84.0 ~ 74.0 *	74.0 ~ 44.0 *
0.50 ~ 30.00	74.0	64.0

Remark:

The limit decreases linearly with the logarithm of the frequency in the range 0.15MHz to 0.50MHz.

3.2. Test Setup



3.3. Test Procedure

The table-top EUT is placed on a non-conductive table 0.8 m above the horizontal ground reference plane, and the back of the EUT is 0.4 m away from the vertical ground reference plane, and at least 0.8 m from any other metal surface or ground plane. The floor-standing EUT is placed on an insulating support 0.1 m above the horizontal ground reference plane, at least 0.8 m away from other metal objects.

Connect EUT to the power mains through an LISN. Where the mains cable supplied by the manufacturer is longer than 1 m, the excess should be folded at the center into a bundle no longer than 0.4 m, so that its length is shortened to 1 m. All the peripherals are connecting to the other LISN.

The EUT was connected to the peripheral equipment through the ISN and linked in normal condition.

Set the test-receiver to quasi peak detect function and average detect function, and to measure the asymmetric mode conducted emission values.

3.4. Test Results

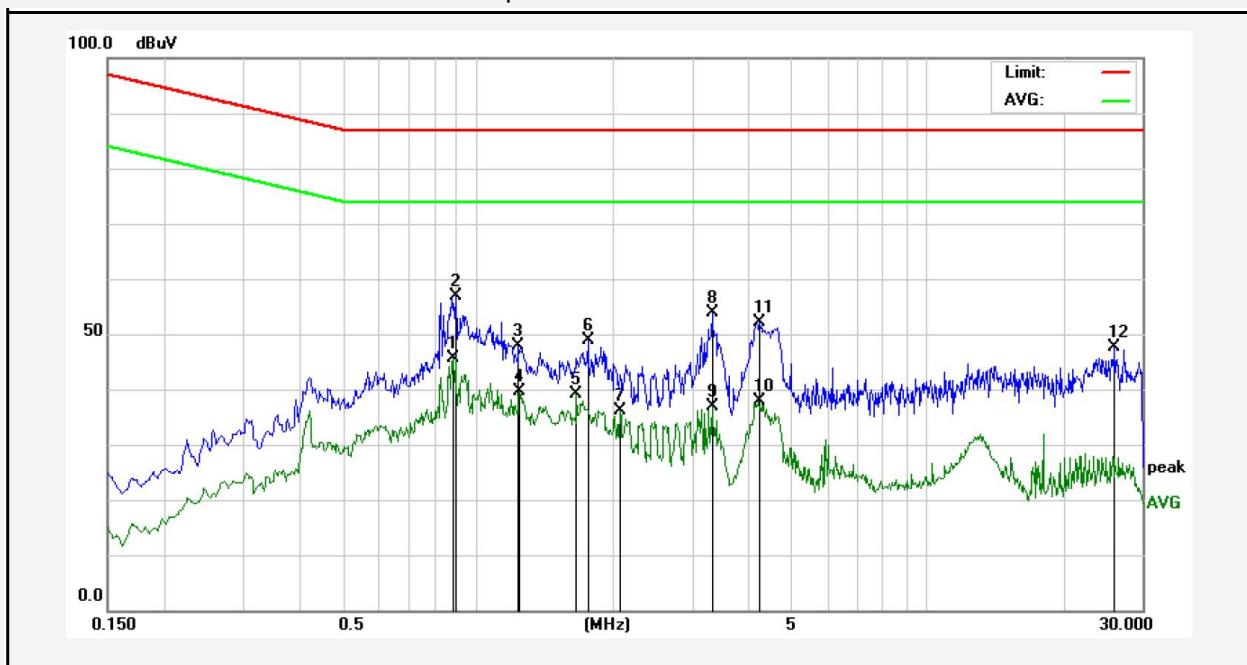
PASS

The test curves are shown in the following pages.



Asymmetric Mode Conducted Emission Test Data

Test Site: 1# Shielded Room
Test Specification: AC 230V, 50Hz
Comment: Telecom Port
Temp.: 23.5°C Hum.: 48%



No.	Freq. (MHz)	Reading (dBuV)	Factor (dB)	Result (dBuV)	Limit (dBuV)	Over Limit (dB)	Detector	Remark
1	0.8820	26.42	19.11	45.53	74.00	-28.47	AVG	
2	0.8980	37.71	19.11	56.82	87.00	-30.18	QP	
3	1.2340	28.71	19.11	47.82	87.00	-39.18	QP	
4	1.2420	20.44	19.11	39.55	74.00	-34.45	AVG	
5	1.6580	20.03	19.11	39.14	74.00	-34.86	AVG	
6	1.7540	29.72	19.11	48.83	87.00	-38.17	QP	
7	2.0740	16.90	19.11	36.01	74.00	-37.99	AVG	
8	3.3260	34.64	19.12	53.76	87.00	-33.24	QP	
9	3.3260	17.74	19.12	36.86	74.00	-37.14	AVG	
10	4.2100	18.80	19.14	37.94	74.00	-36.06	AVG	
11	4.2260	32.94	19.14	52.08	87.00	-34.92	QP	
12	26.0700	27.97	19.62	47.59	87.00	-39.41	QP	

Note: Result = Reading + Factor Over Limit = Result - Limit



4. Radiated Emission Test (Below 1 GHz)

4.1. Test Standard and Limit

Test Standard	EN 55032
---------------	----------

☒ Limit for radiated emissions at frequencies up to 1 GHz for class A equipment

Frequency (MHz)	Distance (Meters)	Field Strengths Limit (dBμV/m)
30 ~ 230	3	50
230 ~ 1000	3	57

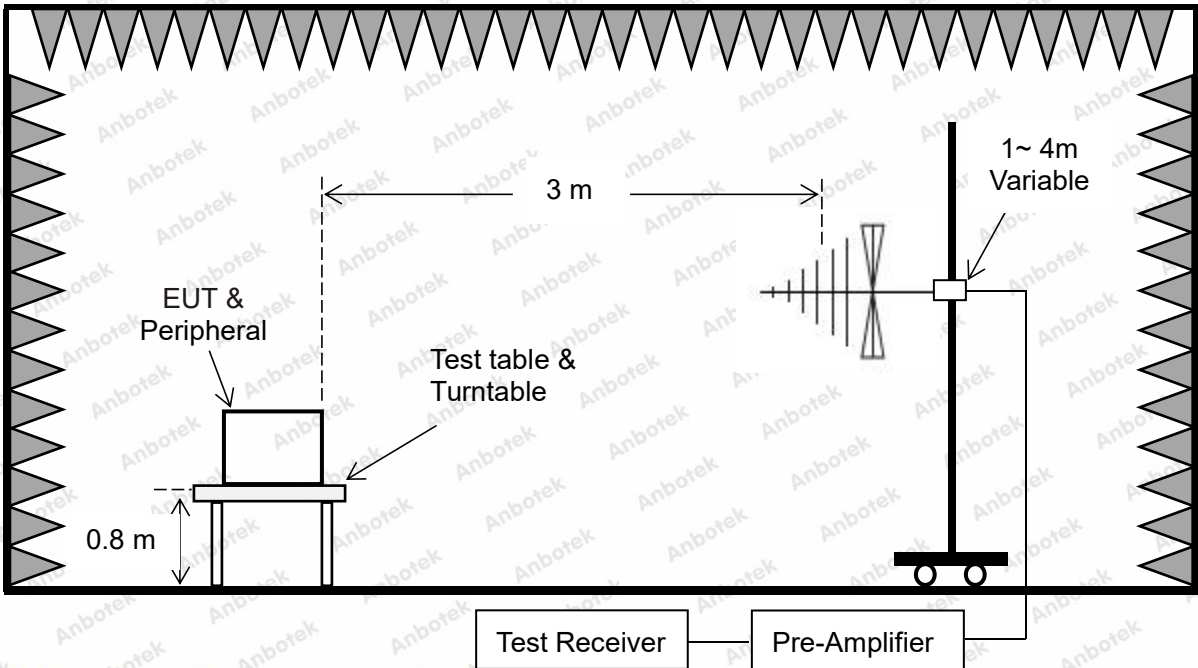
Remark: The lower limit shall apply at the transition frequencies.

☐ Limit for radiated emissions at frequencies up to 1 GHz for class B equipment

Frequency (MHz)	Distance (Meters)	Field Strengths Limit (dBμV/m)
30 ~ 230	3	40
230 ~ 1000	3	47

Remark: The lower limit shall apply at the transition frequencies.

4.2. Test Setup



4.3. Test Procedure

The table-top EUT is placed on a non-conductive table 0.8 m above the horizontal ground reference plane. The floor-standing EUT is placed on an insulating support 0.1 m above the horizontal ground reference plane.

The EUT was set 3 m away from the receiving antenna that was mounted on a non-conductive mast. The antenna can move up and down between 1 to 4 m to find out the maximum emission level.

The turntable can rotate 360 degree to determine the position of the maximum emission level.

The initial testing identified the frequency that has the highest disturbance relative to the limit while operating the EUT in typical modes of operation and cable positions in a test setup representative of typical system configuration.

The identification of the frequency of highest emission with respect to the limit was found by investigating emissions at a number of significant frequencies. The probable frequency of maximum emission had been found and that the associated cable and EUT configuration and mode of operation had been identified.

The bandwidth of the Receiver is set at 120 kHz.

4.4. Test Results

PASS

The test curves are shown in the following pages.



Test item: Radiation Test Polarization: Horizontal
Standard: (RE)EN 55032 Power Source: AC 230V, 50Hz
Frequency Range: 30MHz ~ 1000MHz Temp.(°C)/Hum.(%RH): 22.6(°C)/56%RH
Distance: 3m

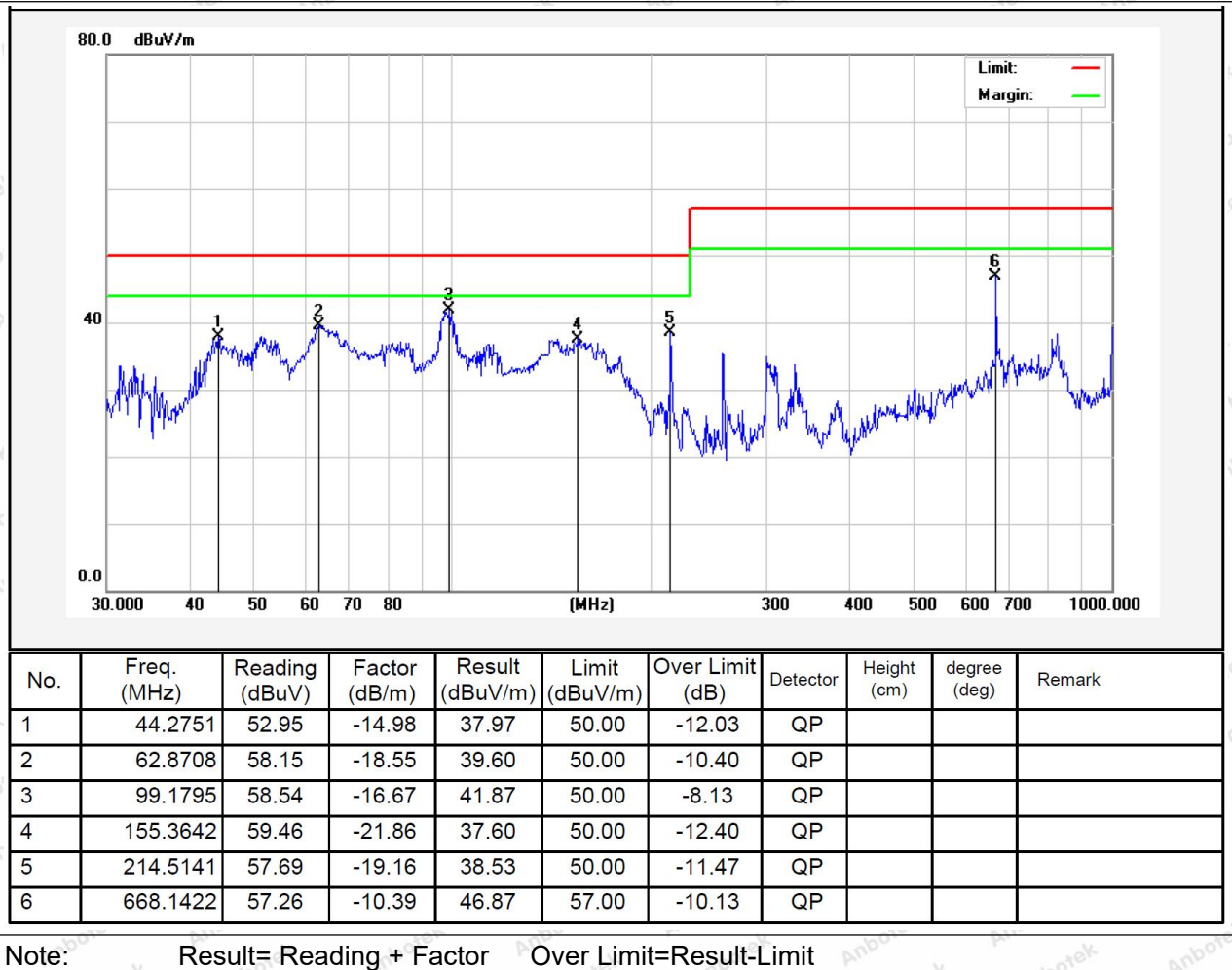


No.	Freq. (MHz)	Reading (dBUV)	Factor (dB/m)	Result (dBUV/m)	Limit (dBUV/m)	Over Limit (dB)	Detector	Height (cm)	degree (deg)	Remark
1	54.8348	52.90	-17.56	35.34	50.00	-14.66	QP			
2	158.1123	57.98	-23.80	34.18	50.00	-15.82	QP			
3	214.5143	59.65	-22.09	37.56	50.00	-12.44	QP			
4	224.5193	55.00	-21.92	33.08	50.00	-16.92	QP			
5	668.1423	50.95	-10.39	40.56	57.00	-16.44	QP			
6	836.2443	48.17	-7.70	40.47	57.00	-16.53	QP			

Note: Result= Reading + Factor Over Limit=Result-Limit



Test item: Radiation Test Polarization: Vertical
Standard: (RE)EN 55032 Power Source: AC 230V, 50Hz
Frequency Range: 30MHz ~ 1000MHz Temp.(°C)/Hum.(%RH): 22.6(°C)/56%RH
Distance: 3m



5. Radiated Emission Test (Above 1GHz)

5.1. Test Standard and Limit

Test Standard	EN 55032
---------------	----------

☒ Limit for radiated emissions at frequencies above 1 GHz for class A equipment

Frequency (MHz)	Distance (Meters)	Field Strengths Limit (dB μ V/m)	
		Peak	Average
1000 ~ 3000	3	76	56
3000 ~ 6000	3	80	60

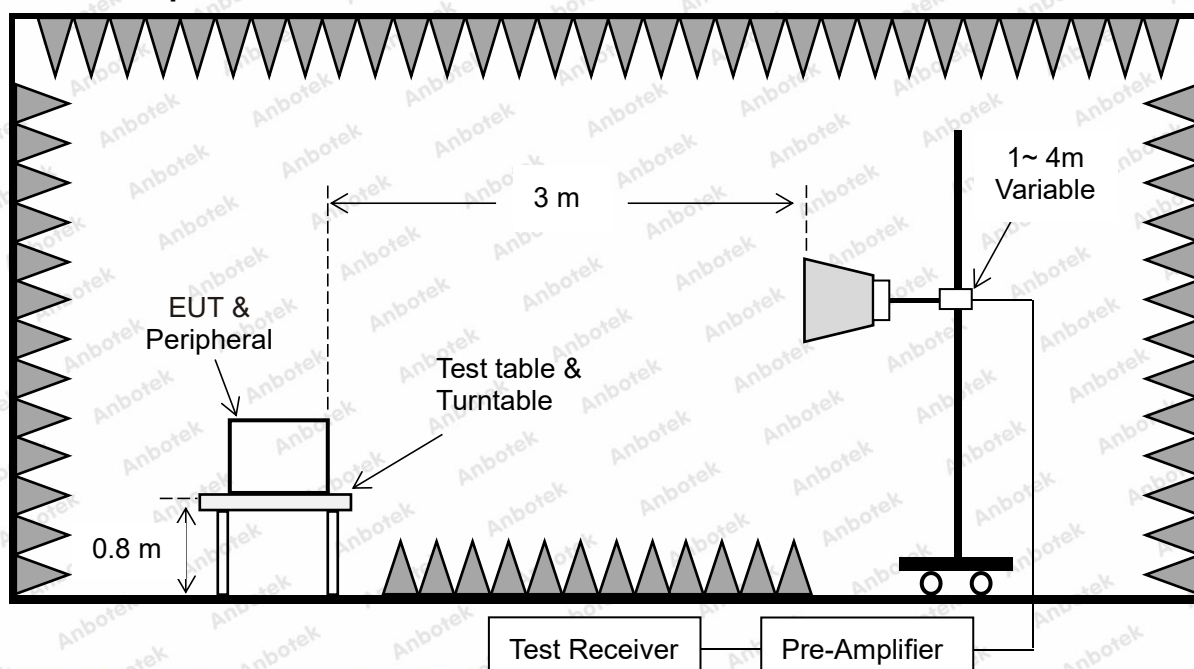
Remark: The lower limit shall apply at the transition frequencies.

☐ Limit for radiated emissions at frequencies above 1 GHz for class B equipment

Frequency (MHz)	Distance (Meters)	Field Strengths Limit (dB μ V/m)	
		Peak	Average
1000 ~ 3000	3	70	50
3000 ~ 6000	3	74	54

Remark: The lower limit shall apply at the transition frequencies.

5.2. Test Setup



5.3. Test Procedure

The table-top EUT is placed on a non-conductive table 0.8 m above the horizontal ground reference plane. The floor-standing EUT is placed on an insulating support 0.1 m above the horizontal ground reference plane.

The EUT was set 3 m away from the receiving antenna that was mounted on a non-conductive mast. The antenna can move up and down between 1 to 4 m to find out the maximum emission level.

The turntable can rotate 360 degree to determine the position of the maximum emission level.

The initial testing identified the frequency that has the highest disturbance relative to the limit while operating the EUT in typical modes of operation and cable positions in a test setup representative of typical system configuration.

The identification of the frequency of highest emission with respect to the limit was found by investigating emissions at a number of significant frequencies. The probable frequency of maximum emission had been found and that the associated cable and EUT configuration and mode of operation had been identified.

The test receiver is set to peak and average detects function.

The bandwidth of the test receiver is set at 1MHz.

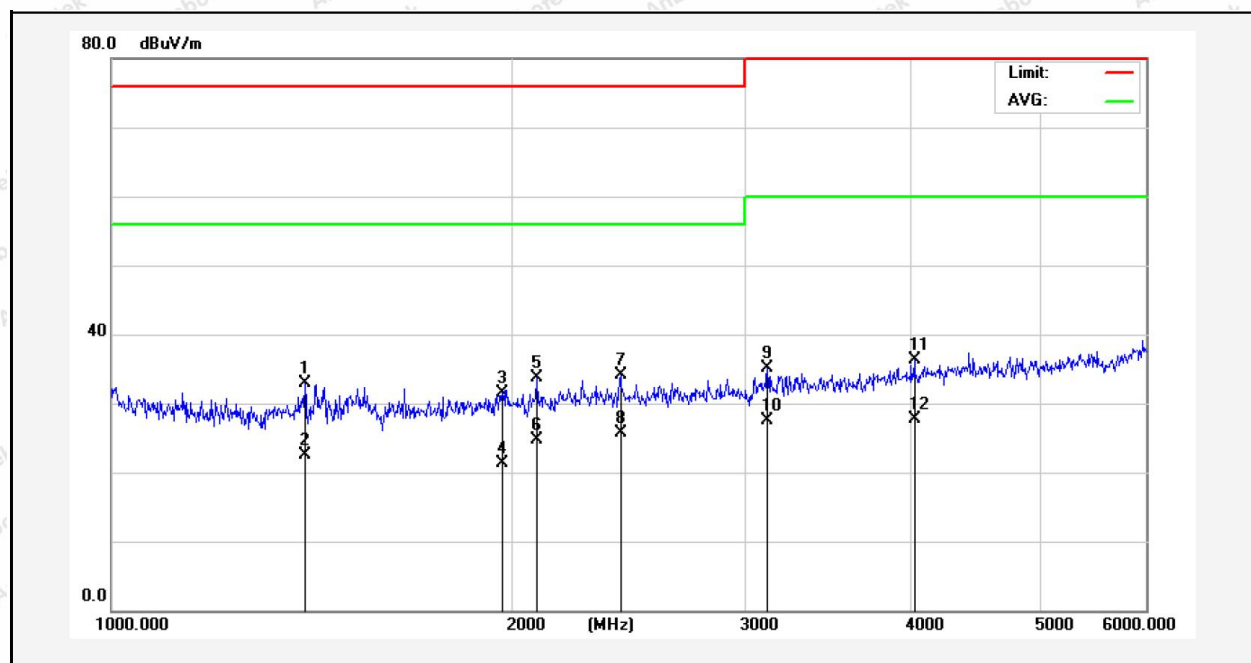
5.4. Test Results

PASS

The test curves are shown in the following pages.



Test item: Radiation Test Polarization: Horizontal
Standard: (RE)EN 55032 Power Source: AC 230V, 50Hz
Frequency Range: 1GHz ~ 6GHz Temp.(°C)/Hum.(%RH): 22.6(°C)/56%RH
Distance: 3m



No.	Freq. (MHz)	Reading (dBuV)	Factor (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Detector	Height (cm)	degree (deg)	Remark
1	1398.023	59.75	-26.91	32.84	76.00	-43.16	peak			
2	1398.023	49.44	-26.91	22.53	56.00	-33.47	AVG			
3	1968.526	56.90	-25.44	31.46	76.00	-44.54	peak			
4	1968.526	46.82	-25.44	21.38	56.00	-34.62	AVG			
5	2088.431	58.74	-25.08	33.66	76.00	-42.34	peak			
6	2088.431	49.85	-25.08	24.77	56.00	-31.23	AVG			
7	2414.629	58.41	-24.40	34.01	76.00	-41.99	peak			
8	2414.629	50.09	-24.40	25.69	56.00	-30.31	AVG			
9	3114.210	57.07	-22.02	35.05	80.00	-44.95	peak			
10	3114.210	49.47	-22.02	27.45	60.00	-32.55	AVG			
11	4016.478	56.06	-19.85	36.21	80.00	-43.79	peak			
12	4016.478	47.48	-19.85	27.63	60.00	-32.37	AVG			

Note: Result=Reading + Factor Over Limit=Result - Limit



Test item: Radiation Test

Polarization:

Vertical

Standard: (RE)EN 55032

Power Source:

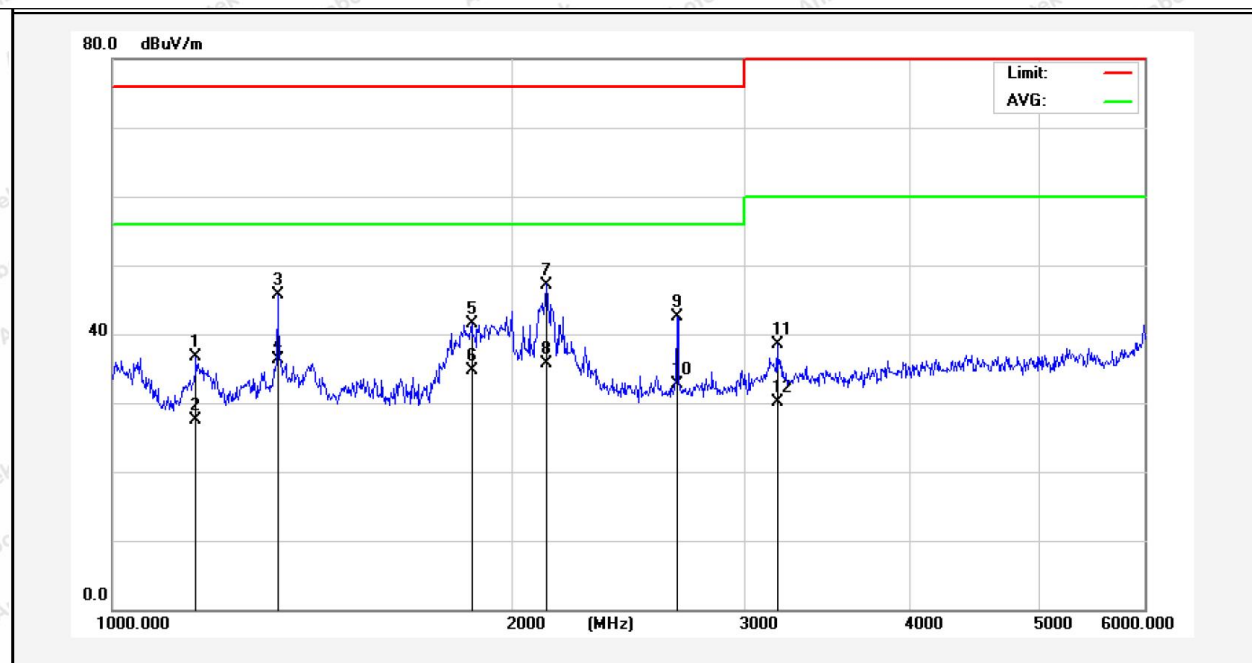
AC 230V, 50Hz

Frequency Range: 1GHz ~ 6GHz

Temp.(°C)/Hum.(%RH):

22.6(°C)/56%RH

Distance: 3m



No.	Freq. (MHz)	Reading (dBuV)	Factor (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Detector	Height (cm)	degree (deg)	Remark
1	1156.193	64.11	-27.46	36.65	76.00	-39.35	peak			
2	1156.193	54.91	-27.46	27.45	56.00	-28.55	AVG			
3	1332.000	72.79	-27.05	45.74	76.00	-30.26	peak			
4	1332.000	63.44	-27.05	36.39	56.00	-19.61	AVG			
5	1865.506	67.44	-25.85	41.59	76.00	-34.41	peak			
6	1865.506	60.64	-25.85	34.79	56.00	-21.21	AVG			
7	2126.188	72.15	-24.95	47.20	76.00	-28.80	peak			
8	2126.188	60.63	-24.95	35.68	56.00	-20.32	AVG			
9	2664.702	66.27	-23.75	42.52	76.00	-33.48	peak			
10	2664.702	56.42	-23.75	32.67	56.00	-23.33	AVG			
11	3170.512	60.32	-21.86	38.46	80.00	-41.54	peak			
12	3170.512	51.98	-21.86	30.12	60.00	-29.88	AVG			

Note: Result=Reading + Factor Over Limit=Result - Limit

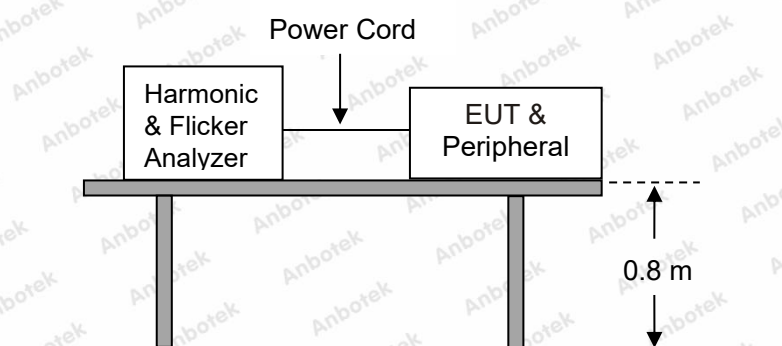


6. Harmonic Current Test

6.1. Test Standard

Test Standard:	EN IEC 61000-3-2
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6.2. Test Setup



6.3. Test Procedure

The table-top EUT is placed on the top of a wooden table 0.8 m above the ground (0.1 m for the floor-standing EUT) and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the necessary for the EUT to be exercised.

6.4. Test Results

The active input power of the EUT is less than 75W. Therefore, according to EN IEC 61000-3-2, no limits are necessary.



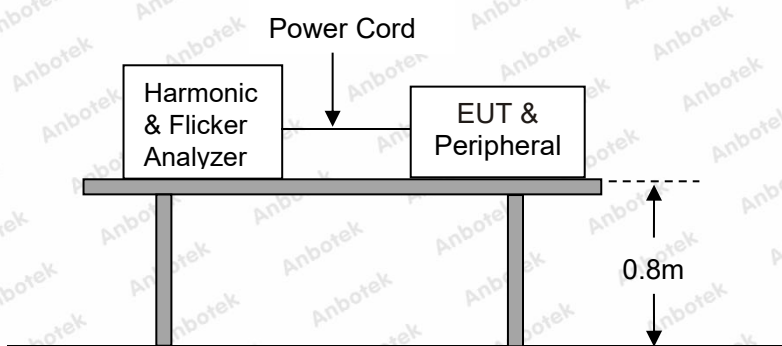
7. Voltage Fluctuations & Flicker Test

7.1. Test Standard

Test Standard:

EN 61000-3-3

7.2. Test Setup



7.3. Test Procedure

The table-top EUT is placed on the top of a wooden table 0.8 m above the ground (0.1 m for the floor-standing EUT) and operated to produce the most unfavorable sequence of voltage changes under normal conditions during the flicker measurement. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

7.4. Test Results

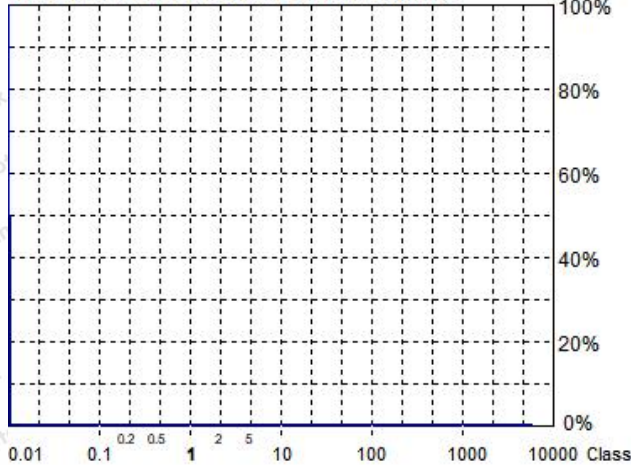
PASS

The test curves are shown in the following pages.



Flicker Test Summary (Run time)

Flicker Emission IEC 61000-4-15 for 230V/50Hz



Actual Flicker (Fli):	0.00
Short-term Flicker (Pst):	0.07
Limit (Pst):	1.00
Long-term Flicker (Plt):	0.00
Limit (Plt):	0.65
Maximum Relative Volt. Change (dmax):	0.00%
Limit (dmax):	4.00%
Relative Steady-state Voltage Change (dc):	0.02%
Limit (dc):	3.30%
Tmax 3.30% (dt):	0.00ms
Limit (dt>Lim):	500ms

Flicker Emission - IEC 61000-3-3, EN 61000-3-3

Urms = 229.5 V P = 10.11 W
Irms = 0.117 A pf = 0.378

Range: 1 A
V-nom: 230 V

Test aborted, Result: PASSED

HAR-1000 EMC-Partner

Full Bar : Actual Values

Empty Bar : Maximum Values

Circles : Average Values

Blue : Current , Green : Voltage , Red : Failed

Urms = 229.5V Freq = 50.013 Range: 1 A
Irms = 0.117A lpk = 0.682A cf = 5.841
P = 10.11W S = 26.78VA pf = 0.378

Test - Time : 10 x 1min = 10min (100 %)

LIN (Line Impedance Network) : L: 0.24ohm +j0.15ohm N: 0.16ohm +j0.10ohm

Limits : Plt : 0.65 Pst : 1.00
dmax : 4.00 % dc : 3.30 %
dtLim: 3.30 % dt>Lim: 500ms

Test aborted, Result: PASSED

	dmax	dc	dt>Lim
	[%]	[%]	[ms]
1	0.000	0.000	0.000



8.1. Test Specification

Test Standard :	EN 55035	
Basic standard :	IEC 61000-4-2: 2008	
Performance criteria:	B	
Test Level :	± 8kV (Air Discharge)	± 4kV (Contact Discharge)

The diagram illustrates the test setup for ESD immunity testing. Key components and dimensions include:

- Wall:** A vertical reference plane.
- EUT & Peripheral:** The Equipment Under Test and its peripherals, placed on a table.
- ESD Generator:** A dashed box representing the source of the ESD pulse, connected to the EUT via a cable.
- VCP (Vocal Control Panel):** A component connected to the EUT via a cable, with a distance of $\geq 1.0\text{m}$ from the Wall.
- HCP (Head Control Panel):** A component connected to the EUT via a cable, with a distance of 0.1m from the EUT.
- GRP (Ground Reference Plane):** A horizontal plane at a height of 0.8m from the EUT, connected to the EUT via a cable.
- Resistors:** Four $470\text{k}\Omega$ resistors are shown, connecting the VCP, HCP, and GRP to the EUT and the ground plane.

c. In the case of painted surface covering a conducting substrate, the following procedure shall be adopted: - If the coating is not declared to be an insulating coating by the equipment manufacturer, then the pointed tip of the generator shall penetrate the coating so as to make contact with the conducting substrate. - Coating declared as insulating by the manufacturer shall only be submitted to the air discharge. - The contact discharge test shall not be applied to such surfaces.



d. In the case of air discharges, the round discharge tip of the discharge electrode shall be approached as fast as possible (without causing mechanical damage) to touch the EUT. After each discharge, the ESD generator (discharge electrode) shall be removed from the EUT. The generator is then retriggered for a new single discharge. This procedure shall be repeated until the discharges are completed. In the case of an air discharge test, the discharge switch, which is used for contact discharge, shall be closed.

e. The test voltage shall be increased from the minimum to the selected test severity level, in order to determine any threshold of failure. The final test level should not exceed the product specification value in order to avoid damage to the equipment.

f. The test shall be performed with both air discharge and contact discharge. The test shall be performed with single discharges. On each pre-selected point at least 10 single discharges (in the most sensitive polarity) shall be applied. For the time interval between successive single discharges an initial value of 1 s is recommended. Longer intervals may be necessary to determine whether a system failure has occurred.

g. Ensure that the applied charge on the EUT has been dis-charged before next ESD pulse.

8.4. Test Results

PASS

Please refer to the following page.



Electrostatic Discharge Test Results

Test Result:	☒ Pass ☐ Fail	Temperature:	23.4℃
Power Supply:	AC 230V, 50Hz	Humidity:	51%
Location		Kind A-Air Discharge C-Contact Discharge	Result
Air discharge: ±2.0 kV, ±4.0 kV, ±8.0 kV		Contact discharge: ±4.0 kV	
DC Port	4 points	C	☒ A ☐ B ☐ C
USB Port	4 points	C	☐ A ☒ B ☐ C
LAN Port	4 points	C	☒ A ☐ B ☐ C
COM Port	4 points	C	☒ A ☐ B ☐ C
VGA Port	4 points	C	☒ A ☐ B ☐ C
Screen	4 points	A	☒ A ☐ B ☐ C
Screw	4 points	C	☒ A ☐ B ☐ C
Slot	4 points	A	☒ A ☐ B ☐ C
Metal	4 points	C	☐ A ☒ B ☐ C
Button	4 points	C	☒ A ☐ B ☐ C
Light	4 points	A	☒ A ☐ B ☐ C
HCP	4 points	C	☒ A ☐ B ☐ C
VCP of the front	4 points	C	☒ A ☐ B ☐ C
VCP of the rear	4 points	C	☒ A ☐ B ☐ C
VCP of the left	4 points	C	☒ A ☐ B ☐ C
VCP of the right	4 points	C	☒ A ☐ B ☐ C
Note: N/A			

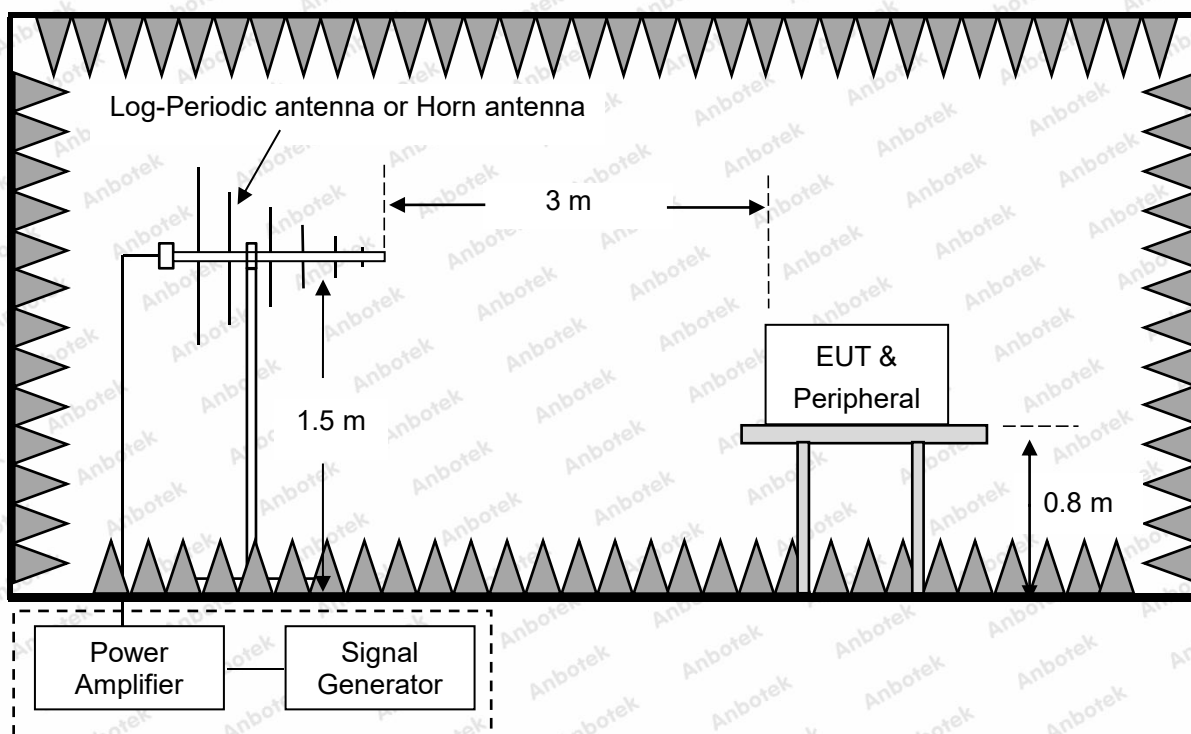


9. RF Field Strength Immunity Test

9.1. Test Specification

Test Standard:	EN 55035		
Basic standard:	IEC 61000-4-3: 2006+A1:2007+A2:2010		
Performance criteria:	A	A	A
Frequency Range:	☒ 80MHz to 1000MHz	☒ Spot frequencies	☐ Additional spot frequencies
Test level:	3 V/m	3 V/m	3 V/m
Modulation:	1kHz Sine Wave, 80%, AM Modulation		
Frequency Step:	1 % of preceding frequency value		
Polarity of Antenna:	Horizontal and Vertical		
Test Distance:	3 m		
Antenna Height:	1.5 m		
Dwell Time:	at least 0.5s		
Spot frequencies: 1800 MHz, 2600 MHz, 3500 MHz and 5000 MHz; Additional spot frequencies: 80 MHz, 120 MHz, 160 MHz, 230 MHz, 434 MHz, 460 MHz, 600 MHz, 863 MHz and 900 MHz .			

9.2. Test Setup



9.3. Test Procedure

The procedure defined in this part requires the generation of electromagnetic fields within which the test sample is placed and its operation observed. To generate fields that are useful for simulation of actual (field) conditions may require significant antenna drive power and the resultant high field strength levels. To comply with local regulations and to prevent biological hazards to the testing personnel, it is recommended that these tests be carried out in a shielded enclosure or semi-anechoic chamber.

a. The antenna is placed 3 m from the equipment. The required field strength is determined by placing the field strength meter(s) on top of or directly alongside the equipment under test and monitoring the field strength meter via a remote field strength indicator outside the enclosure while adjusting the continuous-wave to the antenna.

b. The test shall normally be performed with the generating antenna facing each side of the EUT. When equipment can be used in different orientations (i.e. vertical or horizontal) all sides shall be exposed to the field during the test. When technically justified, some EUTs can be tested by exposing fewer faces to the generating antenna. In other cases, as determined for example by the type and size of EUT or the frequencies of test, more than four azimuths may need to be exposed.

c. The polarization of the field generated by each antenna necessitates testing each selected side twice, once with the antenna positioned vertically and again with the antenna positioned horizontally.

d. The step size of the frequency is set to 1%. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised and to be able to respond. However, the dwell time should not exceed 5 s at each of the frequencies during the scan.

9.4. Test Results

PASS

Please refer to the following page.



RF Field Strength Susceptibility Test Results

Test Result:		☒ Pass ☐ Fail	Temperature:		22.2℃	
Power Supply:		AC 230V, 50Hz		Humidity:		47%
Frequency Range	Antenna Polarity	R.F. Field Strength	Dwell Time	Azimuth		Result
80 MHz ~ 1000 MHz	H / V	3 V/m	1s	Front	☒ A ☐ B ☐ C	
				Rear		
				Left		
				Right		
Spot frequencies	H / V	3 V/m	1s	Front	☒ A ☐ B ☐ C	
				Rear		
				Left		
				Right		
Additional spot frequencies	H / V	3 V/m	1s	Front	☐ A ☐ B ☐ C	
				Rear		
				Left		
				Right		
Note: N/A						



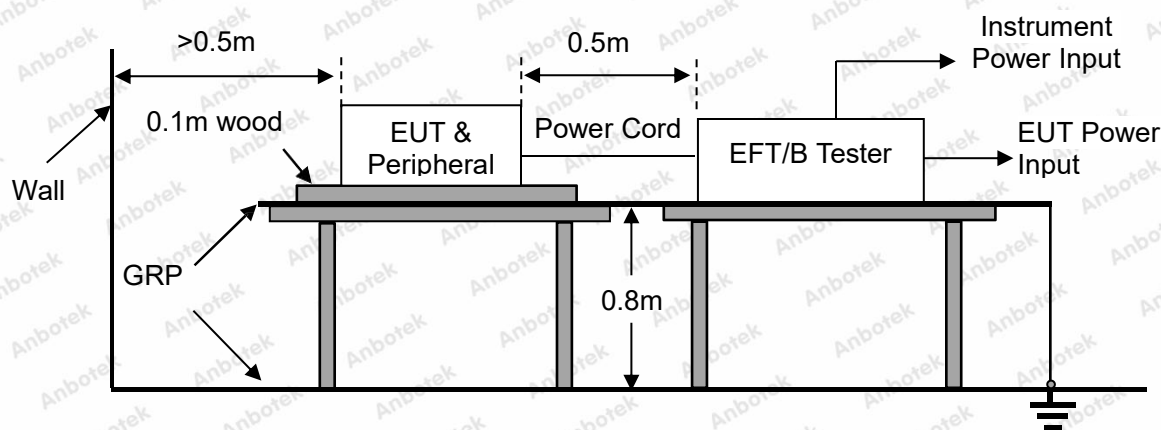
10. Electrical Fast Transient/Burst Immunity Test

10.1. Test Specification

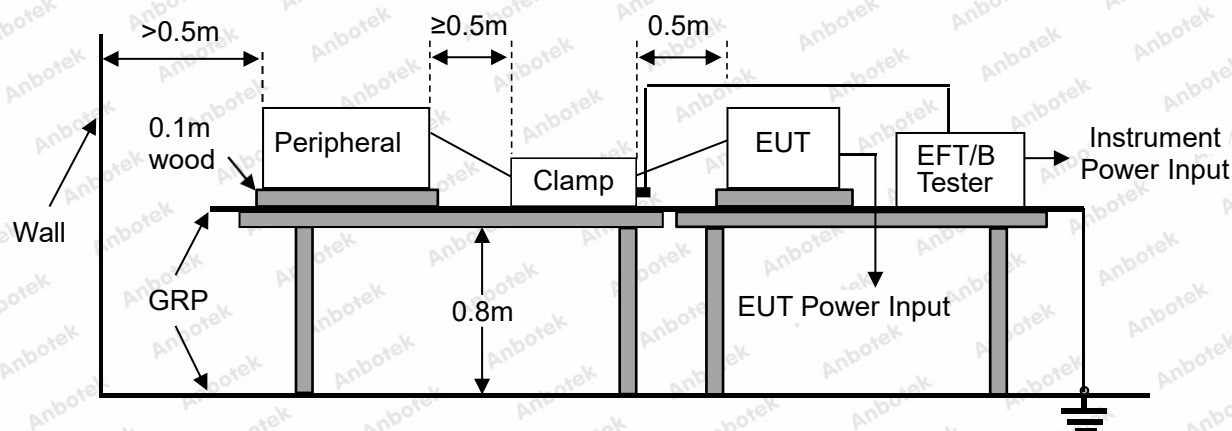
Test Standard:	EN 55035
Basic standard:	IEC 61000-4-4: 2012
Performance criteria:	B
Test Level:	☒ 1 kV, AC mains power ports
	☐ 0.5 kV, DC network power ports
	☐ 0.5 kV, Analogue/digital data ports

10.2. Test Setup

AC mains power ports and DC network power ports:



Analogue/digital data ports:



10.3. Test Procedure

The table-top EUT is placed on a table that is 0.8 m height, a ground reference plane is placed on the table, and uses 0.1 m insulation between the EUT and ground reference plane. The floor-standing EUT is placed on a ground reference plane and insulated from it by an insulating support with a thickness of 0.1 m. This reference ground plane shall project beyond the EUT by at least 0.1 m on all sides and the minimum distance between EUT and all other conductive structure, except the ground plane beneath the EUT, shall be more than 0.5 m.

All cables to the EUT shall be placed on the insulation support 0.1 m above the ground reference plane. Cables not subject to electrical fast transients shall be routed as far as possible from the cable under test to minimize the coupling between the cables.

10.4. Test Results

PASS

Please refer to the following page.



Electrical Fast Transient/Burst Test Results

Test Result:	☒ Pass ☐ Fail	Temperature:	23.4℃	
Power Supply:	AC 230V, 50Hz	Humidity:	51%	
Ports	Polarity	Inject Time(s)	Test Voltage (kV)	Result
AC mains power ports	±	120 s	1.0 kV	☒ A ☐ B ☐ C
DC network power ports	±	120 s	0.5 kV	☐ A ☐ B ☐ C
Analogue/digital data ports (xx Line)	±	120 s	0.5 kV	☐ A ☐ B ☐ C
Note: N/A				

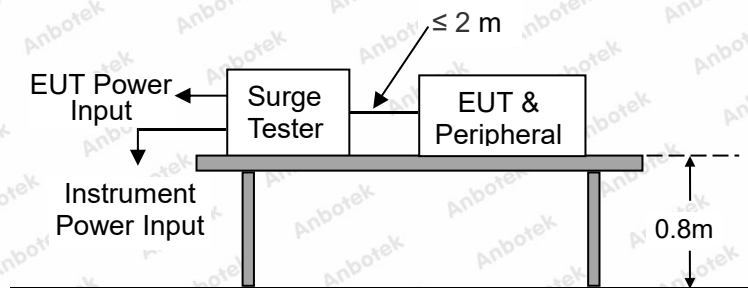


11. Surge Immunity Test

11.1. Test Specification

Test Standard:		EN 55035
Basic standard:		IEC 61000-4-5: 2014+A1:2017
Test level	AC power port:	☒ 1 kV, Line to Line, Criterion B
		☒ 2kV, Line to Ground, Criterion B
	DC network power port:	☐ 0.5kV, Line to Reference Ground, Criterion B
	Coaxial or shielded port:	☐ 0.5kV, Shield to Ground, Criterion B
	Unshielded symmetrical port:	☐ 1 kV and 4 kV, Lines to Ground , Primary protection, Criterion C
		☐ 1 kV, Lines to Ground , Non primary protection, Criterion C
Number of surges		5 (for each combination of parameters)
Repetition rate		1 minute / time
Polarity:		Positive / Negative
Phase angle:		90°, 270° (Only AC mains power ports)

11.2. Test Setup



11.3. Test Procedure

Table-top EUT is placed on a table of 0.8 m heights above a metal ground reference plane. Floor standing EUT is placed on a ground reference plane and insulated from it by an insulating support with a thickness of 0.1 m. The length of the power cord between the EUT and the coupling/decoupling network is not more than 2 m, and the length of the interconnection line between the EUT and the coupling/decoupling network is not more than 2 m. The tests were done at repetition rate 1 per minute.

11.4. Test Results

PASS

Please refer to the following page.

Shenzhen Anbotech Compliance Laboratory Limited

Address:1/F.,Building D,Sogood Science and Technology Park, Sanwei Community,
Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China.
Tel:(86) 0755-26066440 Fax:(86) 0755-26014772 Email:service@anbotech.com

Code: AB-EMC-02-c



Hotline

400-003-0500

www.anbotech.com.cn



Surge Immunity Test Results

Test Result:	☒ Pass ☐ Fail	Temperature :	23.4℃		
Power Supply :	AC 230V, 50Hz	Humidity :	51%		
Location	Polarity	Phase Angle	Number of Pulse	Pulse Voltage (kV)	Result
☒ AC power port (Waveform: 1.2 us / 50 us (8 us / 20us))					
L-N	+	☐ 0° ☒ 90° ☐ 180° ☐ 270°	5	0.5, 1kV	☒ A ☐ B ☐ C
	-	☐ 0° ☐ 90° ☐ 180° ☒ 270°	5	0.5, 1kV	☒ A ☐ B ☐ C
L-GND	+	☐ 0° ☒ 90° ☐ 180° ☐ 270°	5	0.5, 1, 2kV	☒ A ☐ B ☐ C
	-	☐ 0° ☐ 90° ☐ 180° ☒ 270°	5	0.5, 1, 2kV	☒ A ☐ B ☐ C
N-GND	-	☐ 0° ☒ 90° ☐ 180° ☐ 270°	5	0.5, 1, 2kV	☒ A ☐ B ☐ C
	+	☐ 0° ☐ 90° ☐ 180° ☒ 270°	5	0.5, 1, 2kV	☒ A ☐ B ☐ C
☐ DC network power ports (Waveform: 1.2 us / 50 us (8 us / 20us))					
Line to Reference ground	+	/	5	0.5kV	☐ A ☐ B ☐ C
	-	/	5	0.5kV	☐ A ☐ B ☐ C
☐ Analogue/digital data ports (Waveform: 10 us / 700 us (5 us / 320us)) :					
Lines to ground	+	/	5	0.5, 1kV	☐ A ☐ B ☐ C
	-	/	5	0.5, 1kV	☐ A ☐ B ☐ C
☐ Analogue/digital data ports (Waveform: 10 us / 700 us (5 us / 320us)) :					
Lines to ground	+	/	5	0.5, 1, 2, 4kV	☐ A ☐ B ☐ C
	-	/	5	0.5, 1, 2, 4kV	☐ A ☐ B ☐ C
☐ Analogue/digital data ports (Waveform: 1.2 us / 50 us (8 us / 20us)): Coaxial or shielded lines					
Shield to ground	+	/	5	0.5kV	☐ A ☐ B ☐ C
	-	/	5	0.5kV	☐ A ☐ B ☐ C
Note: N/A					



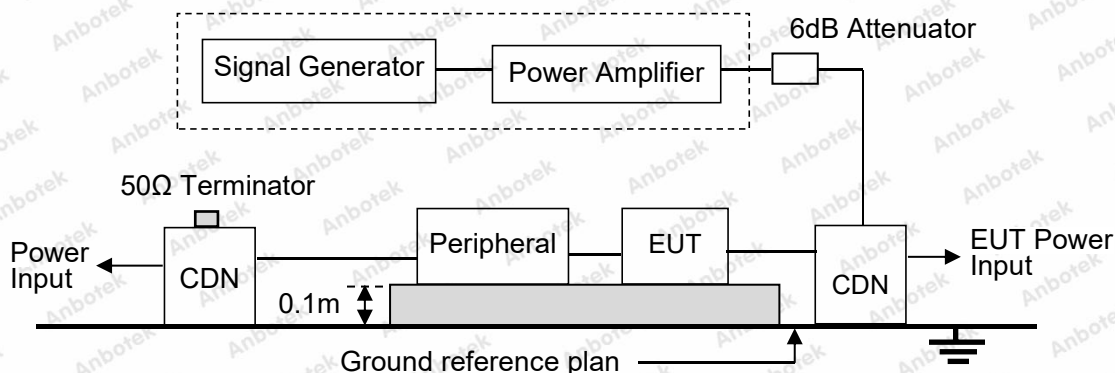
12. Injected Currents Susceptibility Test

12.1. Test Specification

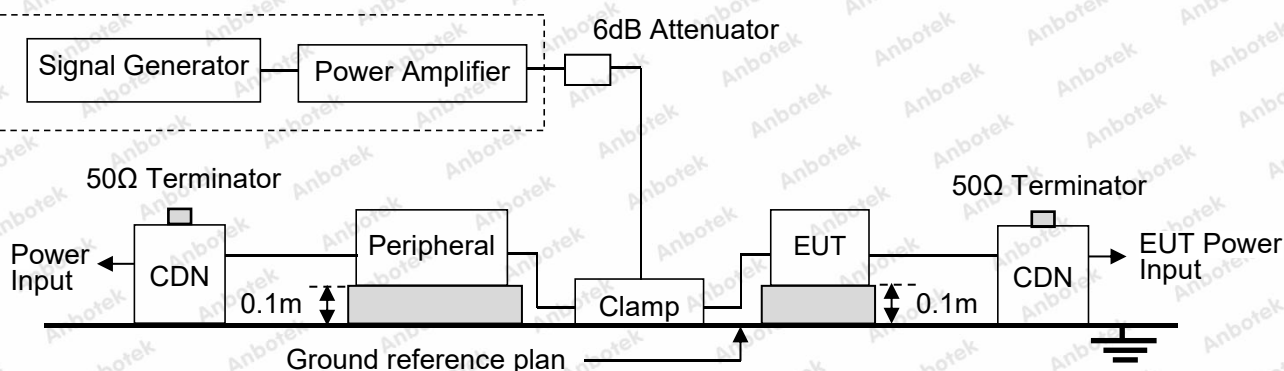
Test Standard:	EN 55035		
Basic standard:	IEC 61000-4-6: 2013		
Performance criteria:	A		
Frequency range:	0.15MHz to 10MHz	10MHz to 30MHz	30MHz to 80MHz
Test level:	3V	3V to 1V	1V
Modulation:	AM 80%, 1kHz sine-wave		
Frequency Step:	1% of fundamental		

12.2. Test Setup

CDN injection:



Clamp injection:



12.3. Test Procedure

- a. The EUT and peripheral are placed on an insulating support of 0.1 m height above a ground reference plan. The distance between EUT and CDN is 0.1 m to 0.3 m. All cables exiting the EUT are supported at a height of at least 30 mm above the ground reference plan.
- b. The frequency range is swept from 150 kHz to 80MHz, with the signal 80% amplitude modulated with a 1 kHz sine wave. The rate of sweep did not exceed 1.5×10^{-3} decade/s. The frequency range is swept incrementally. The step size was 1% of fundamental from 0.15MHz to 80MHz.
- c. The dwell time at each frequency isn't less than the time necessary for the EUT to be able to respond.

12.4. Test Results**PASS**

Please refer to the following page.



Injected Currents Susceptibility Test Results

Test Result:	☒ Pass ☐ Fail	Temperature:	23.2℃
Power Supply:	AC 230V, 50Hz	Humidity:	50%
Frequency Range (MHz)	Injected Position	Strength (Un-modulated)	Result
0.15 ~ 10	AC Mains	3V	☒ A ☐ B ☐ C
10 ~ 30	AC Mains	3V to 1V	☒ A ☐ B ☐ C
30 ~ 80	AC Mains	1V	☒ A ☐ B ☐ C
0.15 ~ 10		3V	☐ A ☐ B ☐ C
10 ~ 30		3V to 1V	☐ A ☐ B ☐ C
30 ~ 80		1V	☐ A ☐ B ☐ C
Note: N/A			

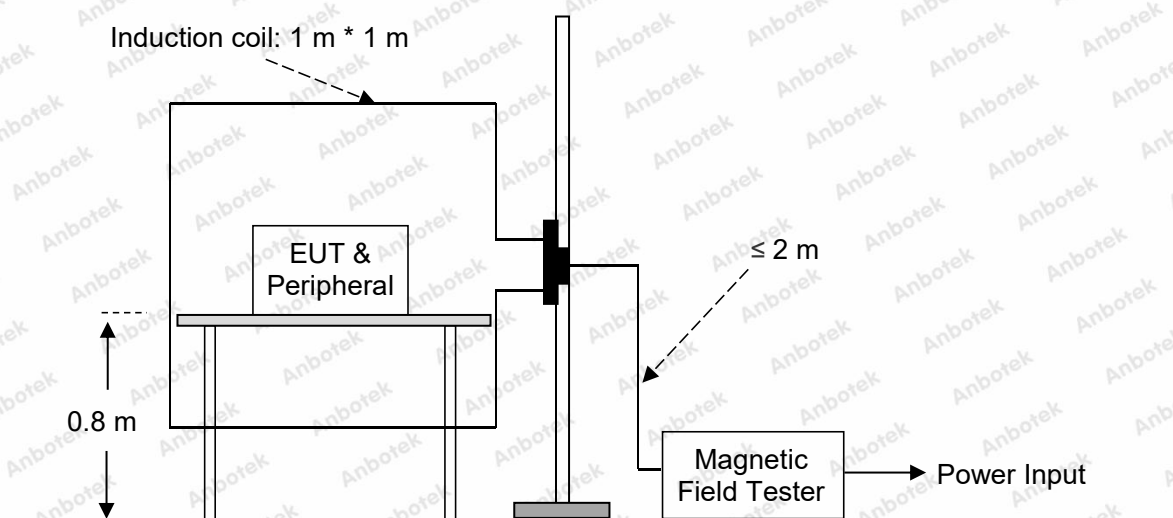


13. Power Frequency Magnetic Field Immunity Test

13.1. Test Specification

Test Standard:	EN 55035
Basic Standard	IEC 61000-4-8: 2009
Performance criteria	A
Test level	1A/m

13.2. Test Setup



13.3. Test Procedure

Table-top EUT is placed on a table that is 0.8 m height. Floor standing EUT is placed on a ground reference plane and insulated from it by an insulating support with a thickness of 0.1 m.

The EUT is placed in the middle of an induction coil. The proximity method is used when the EUT does not fit into the standard inductive coil

13.4. Test Results

Not applicable.

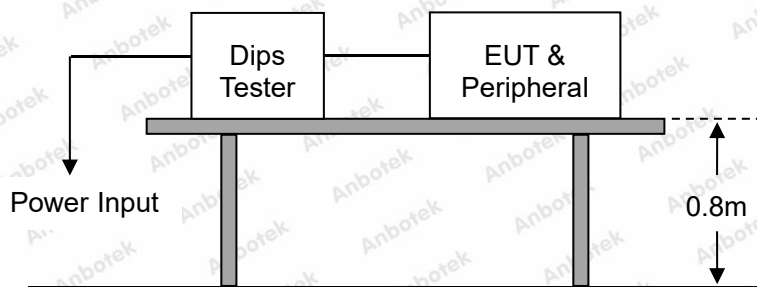


14. Voltage Dips and Interruptions Immunity Test

14.1. Test Specification

Test Standard:	EN 55035
Basic standard:	IEC 61000-4-11: 2020
Test level:	☒ 0%, 0.5 period, Criterion B
	☒ 70%, 25 periods for 50Hz, Criteria C
	☒ 0%, 250 periods for 50Hz, Criteria C
	☐ 70%, 30 periods for 60Hz, Criteria C
	☐ 0%, 300 periods for 60Hz, Criteria C

14.2. Test Setup



14.3. Test Procedure

a. Where the equipment has a rated voltage the following shall apply:

- If the voltage range does not exceed 20% of the lower voltage specified for the rated voltage range, a single voltage within that range may be specified as a basis for test level specification.
- In all other cases, the test procedure shall be applied for both the lowest and highest voltages declared in the voltage range.

b. Test Conditions

- Select operated voltage and frequency of EUT - Test of interval: 10 sec.
- Level and duration: Sequence of 3 dips/interrupts.
- Voltage rise (and fall) time: 1.5 μ s.

c. Changes to occur at 0 degree crossover point of the voltage waveform.

14.4. Test Results

PASS

Please refer to the following page.



Voltage Dips and Interruptions Test Results

Test Result:	☒ Pass ☐ Fail	Temperature :	23.4℃
Power Supply :	AC 230V, 50Hz	Humidity :	51%
Test Level % UT	Voltage Dips & Short Interruptions % UT	Duration (in periods)	Result
0	100	0.5P	☒ A ☐ B ☐ C
70	30	25P	☒ A ☐ B ☐ C
Test Level % UT	Voltage Dips & Short Interruptions % UT	Duration (in periods)	Result
0	100	250P	☐ A ☐ B ☒ C
Note: N/A			



APPENDIX I -- TEST SETUP PHOTOGRAPH

Photo of Power Line Conducted Emission Test

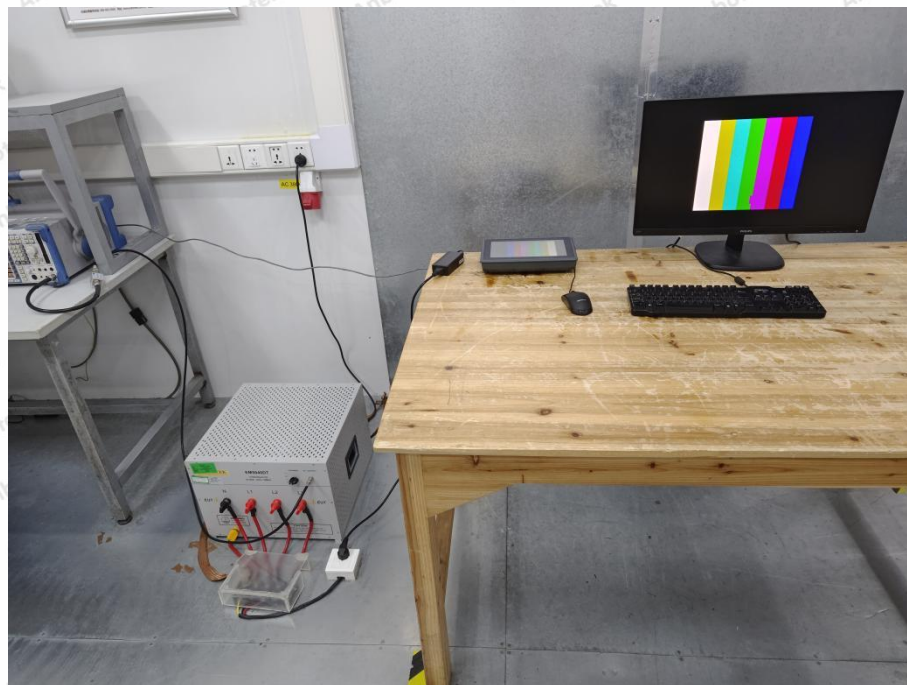


Photo of Asymmetric Mode Conducted Emission at Telecom Port



Photo of Radiated Emission Test (Below 1 GHz)



Photo of Radiated Emission Test (Above 1GHz)



Photo of Harmonic Current And Flicker Test



Photo of Electrostatic Discharge Immunity Test

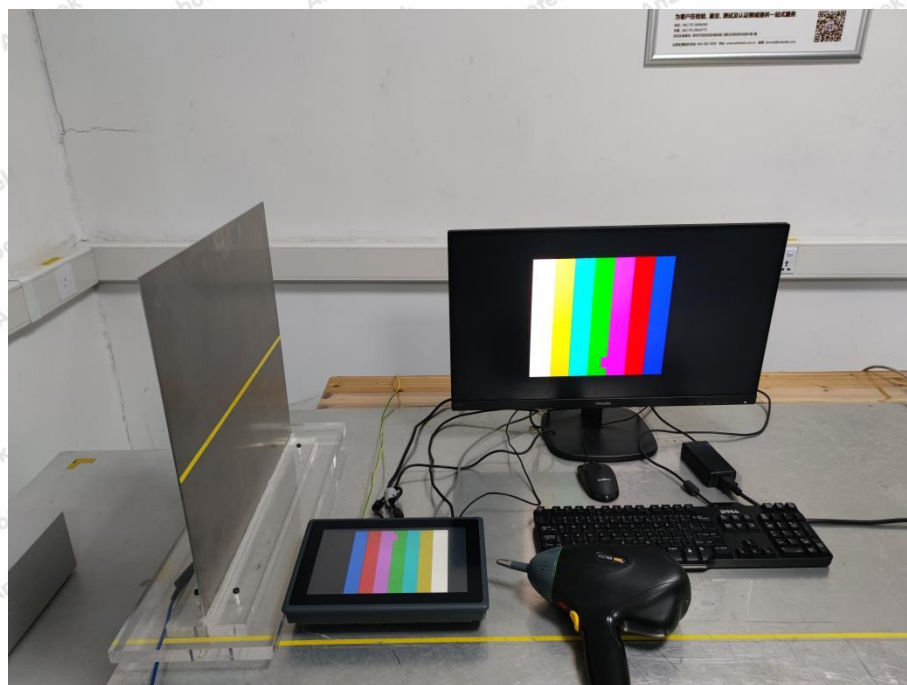


Photo of RF Field Strength Immunity Test

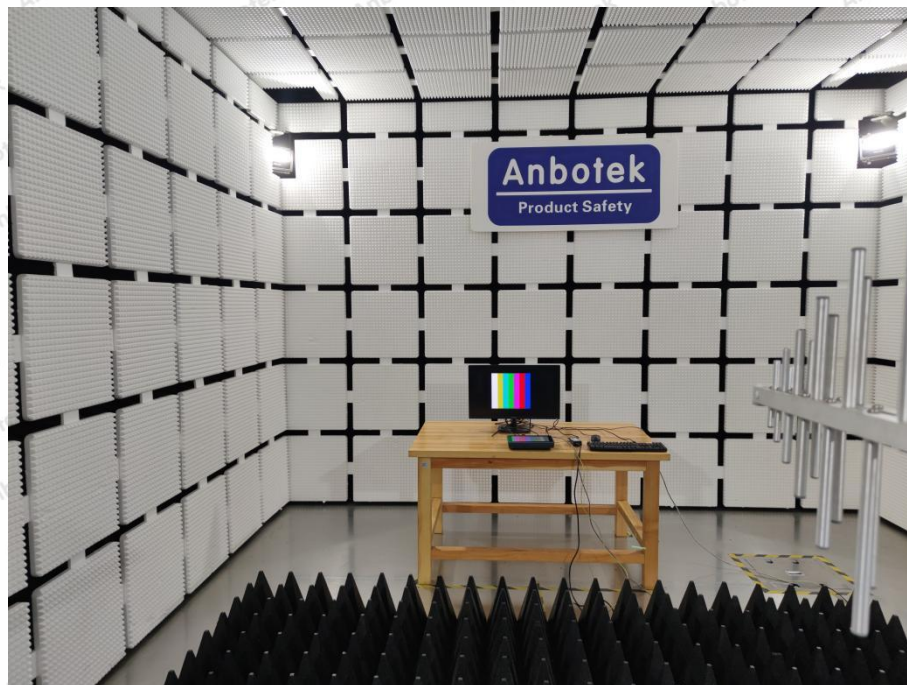


Photo of Electrical Fast Transient/Burst Immunity Test



Photo of Surge Immunity Test



Photo of Injected Currents Susceptibility Test

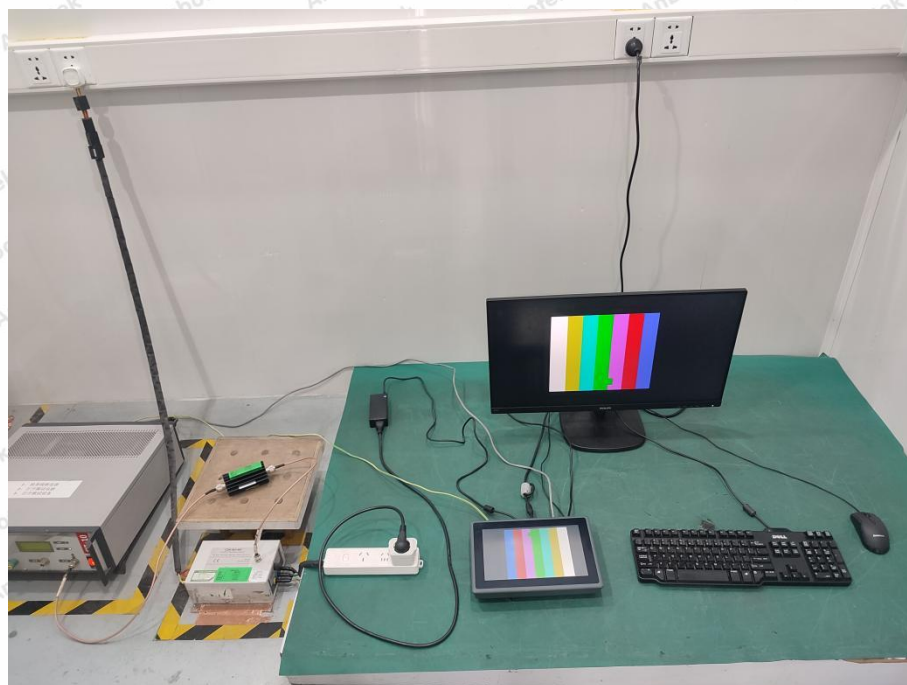


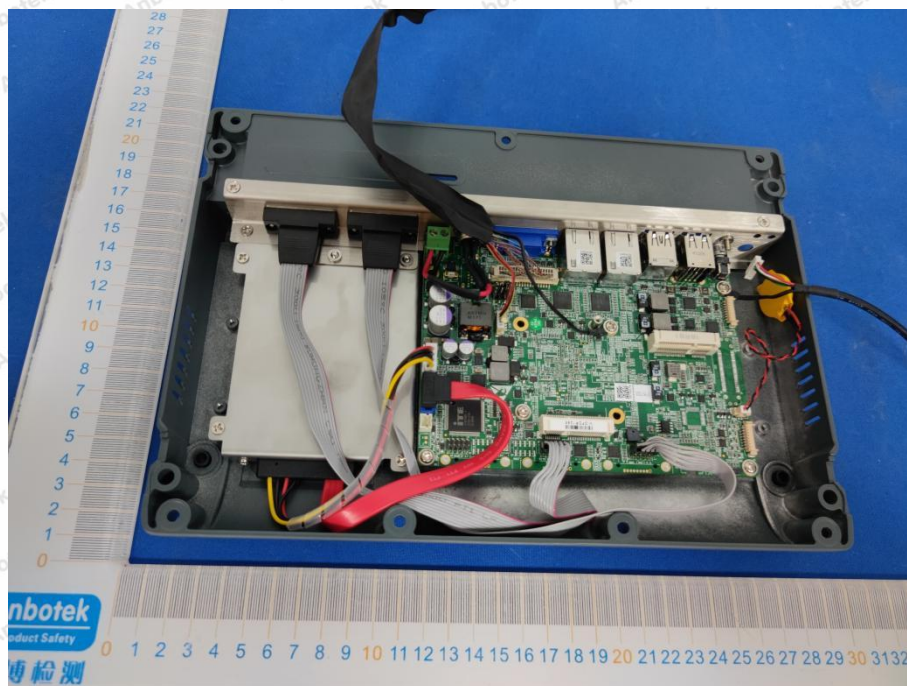
Photo of Voltage Dips and Interruptions Immunity Test



APPENDIX II -- EXTERNAL PHOTOGRAPH





APPENDIX III -- INTERNAL PHOTOGRAPH

CE Label

1. The CE conformity marking must consist of the initials 'CE' taking the following form:

If the CE marking is reduced or enlarged, the proportions given in the above graduated drawing must be respected.

2. The CE marking must have a height of at least 5 mm except where this is not possible on account of the nature of the apparatus.
3. The CE marking must be affixed to the product or to its data plate. Additionally it must be affixed to the packaging, if any, and to the accompanying documents.
4. The CE marking must be affixed visibly, legibly and indelibly.

It must have the same height as the initials 'CE'.

----- End of Report -----

